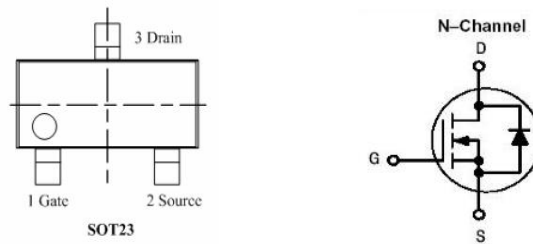




GENERAL DESCRIPTION

The RZC2317 is the P-Channel logic enhancement mode power field effect transistors are produced using high cell density, This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application, notebook computer power management and other battery powered circuits where high-side switching.

PIN CONFIGURATION



FEATURES

- -20V/-4.7A, $R_{DS(ON)} = 32m\Omega$ $V_{GS} = -4.5V$ (MAX.)
 $R_{DS(ON)} = 40m\Omega$ $V_{GS} = -2.5V$ (MAX.)
 $R_{DS(ON)} = 55m\Omega$ $V_{GS} = -1.8V$ (MAX.)
- Super high density cell design for extremely low
- Exceptional on-resistance and maximum DC current capability
- Full RoHS compliance
- SOT-23 package design

APPLICTIONS

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch

ORDERING INFORMATION

Part Number	Package	Top Marking	Packing
RZC2317	SOT-23	2317	3000PCS/Real

**MAXIMUM RATINGS** ($T_a = 25^\circ\text{C}$)

Parameter	Symbol	Value	Units	
Drain to Source Voltage	V_{DSS}	-20	V	
Gate to Source Voltage	V_{GSS}	± 12	V	
Continuous Drain Current	25°C	I_D	-4.7	A
	70°C		-3.8	A
Pulsed Drain Current	$I_{D(pulse)}$	-18.8	A	
Maximum Power Dissipation	25°C	P_D	1	W
Thermal Resistance, Junction to Case	$R_{\theta JC}$	125	$^\circ\text{C/W}$	
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	80	$^\circ\text{C/W}$	
Operating Junction Temperature	T_J	150	$^\circ\text{C}$	
Storage Temperature	T_{STG}	-55-+150	$^\circ\text{C}$	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)	T_L	260	$^\circ\text{C}$	

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

**ELECTRICAL CHARACTERISTICS** (TA = 25°C)

Parameter	Symbol	Test Conditions	MIN	TYP	MAX	Units
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _{DS} =-250μA	-20			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-16V, V _{GS} =0V			-1	μA
Gate Leakage Current	I _{GSS}	V _{GS} =±12V, V _{DS} =0V			±100	nA
Gate threshold voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =-250μA			-2.5	V
Drain to Source On-state Resistance	R _{DS(ON)}	V _{GS} =-4.5V, I _D =-4.0A		25	32	mΩ
		V _{GS} =-2.5V, I _D =-2.0A		32	40	
		V _{GS} =-1.8V, I _D =-1.5A		42	55	
Input Capacitance	C _{iss}	V _{DS} =-15V , V _{GS} =0V , f=1MHz		2280	3192	pF
Output Capacitance	C _{oss}			220	308	pF
Reverse Transfer Capacitance	C _{rss}			187	262	pF
Total Gate Charge	Q _g	V _{DS} =-15V , V _{GS} =-4.5V , I _D =-4A		27	38	nC
Gate-Source Charge	Q _{gs}			3.6	5.0	nC
Gate-Drain Charge	Q _{gd}			6.5	9	nC
Turn-On Delay Time	T _{d(on)}	V _{DS} =-15V, V _{GS} =-10V R _G =3.3Ω, I _D =-1A		9.2	18.4	nS
Rise Time	T _r			59	106	
Turn-Off Delay Time	T _{d(off)}			99	198	
Fall Time	T _f			71	142	
Drain-Source Diode Forward Voltage	V _{SD}	I _S =-1A, V _{GS} =0V, T _C =25°C			-1.0	V
Maximum Continuous Drain-Source Diode Forward Current	I _D	T _C =25°C			-4.7	A
Maximum Pulse Drain-Source Diode Forward Current	I _{DSM}				-18.8	A
Reverse Recovery Time	t _{rr}	I _F =-4A, T _J =25°C		52		nS
Reverse Recovery Charge	Q _{rr}	Di/Dt=100A/μS		28		nC

Note : 1.The data tested by surface mounted on a 1 inch²FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width≤300us , duty cycle ≤ 2%

3.The power dissipation is limited by 150°C junction temperature

5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation



TYPICAL CHARACTERISTICS

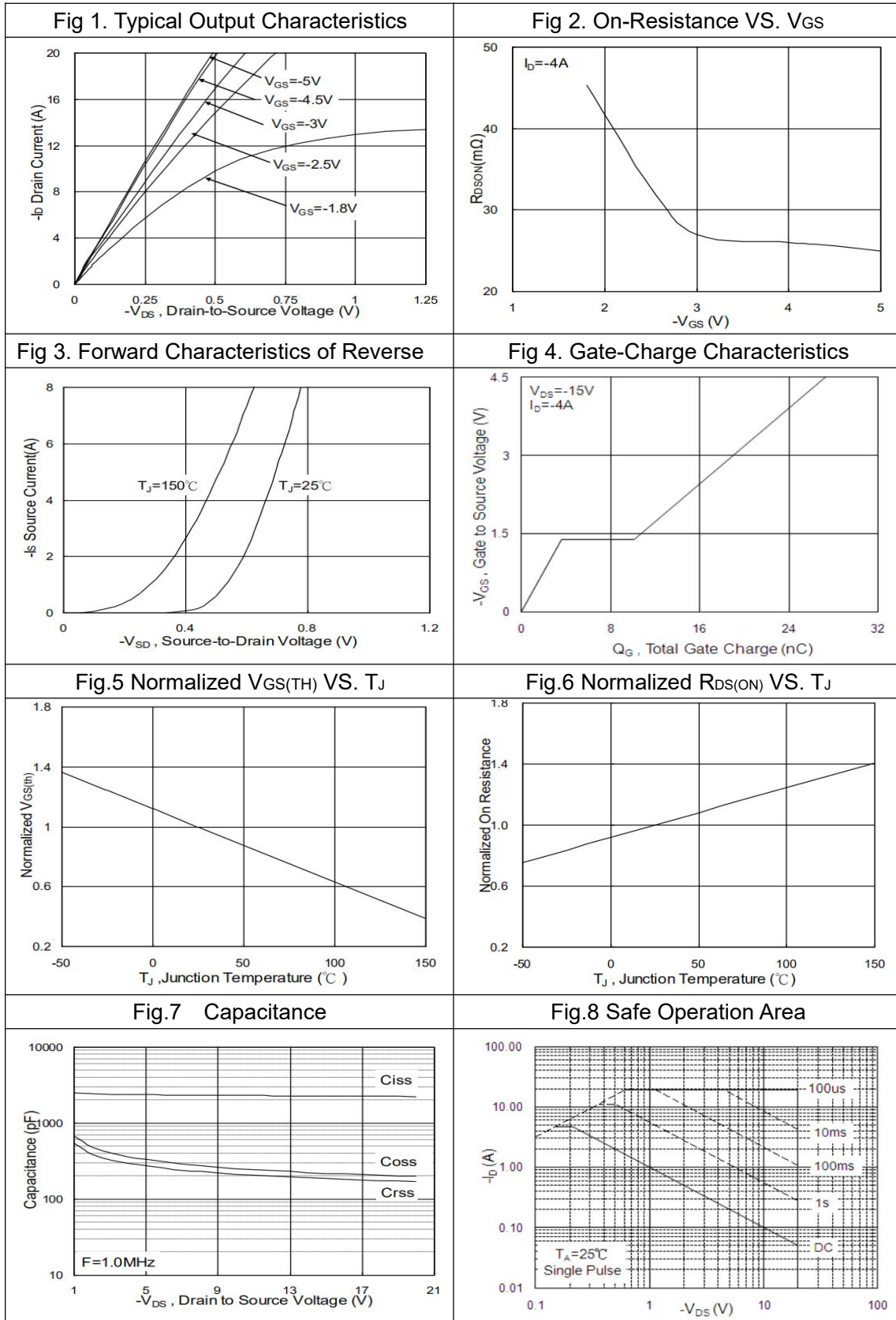
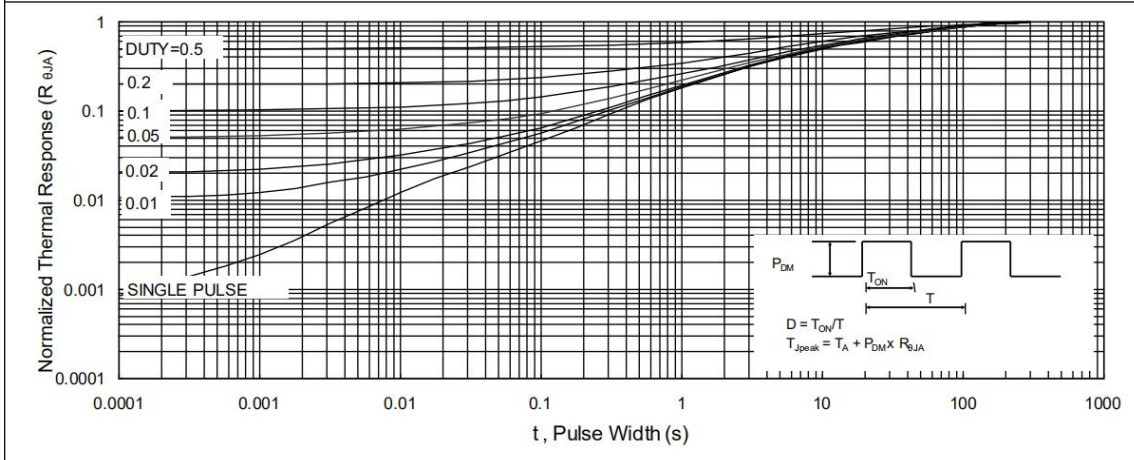




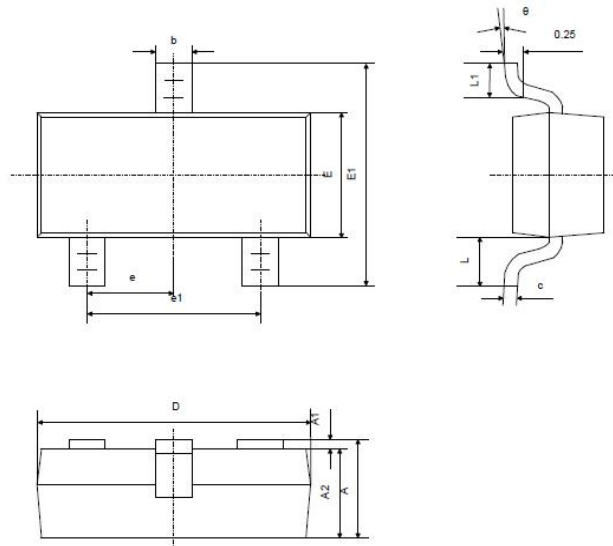
Fig.9 Maximum Effective Transient Thermal Impedance, Junction to Case





PACKAGE DIMENSIONS

SOT-23



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	0.889	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
c	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.950TYP		0.037TYP	
e1	1.800	2.000	0.071	0.079
L	0.550REF		0.022REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	6°

Note:

1. Dimension D does not include mold flash, protrusions or gate burrs. mold flash, protrusions or gate burrs shall not exceed 0.10mm per side.
2. Dimension E1 does not include inter-lead flash or protrusion. Inter-lead flash or protrusion shall not exceed 0.1mm per side.